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AEHR TEST SYSTEMS ANNOUNCES FOLLOW-ON FOX™-1 PARALLEL TEST SYSTEM AND WAFERPAK™ CONTACTOR ORDERS

Fremont, CA (May 6, 2013) - Aehr Test Systems (**Nasdaq: AEHR**), a worldwide supplier of semiconductor test and burn-in equipment, announced today that it has received over $4 million in follow-on orders for multiple FOX-1 Parallel Test Systems and WaferPak contactors from a leading manufacturer of semiconductor memory devices. The orders include 30% down payments to lock in deliveries and a volume pricing agreement.

"We are very pleased to have received these follow-on orders," said Gayn Erickson, president and chief executive officer at Aehr Test Systems. "The orders indicate to us that our customer is achieving ongoing cost and through-put benefits with the FOX full wafer contact solution. Further, they emphasize the close relationship that we have with our customer and their continuing commitment to Aehr Test's products for their wafer sort needs."

The FOX systems, using Aehr Test WaferPak contactors, allow parallel testing of thousands of die on a wafer with only a single touchdown. Aehr Test's FOX family of products is focused on high reliability test needs and long-duration full wafer burn-in and test of products such as automotive ICs, memories and devices with embedded memories, including microcontrollers and smart card devices.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test’s products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX and WaferPak contactor technologies, acceptance by customers of the WaferPak contactors shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test’s recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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